

N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$ Max.	I _D (A)	Q _g (Typ.)		
	0.0064 at V _{GS} = 10 V	75 ^a			
80	0.0070 at V _{GS} = 6.0 V	65 ^a	17.1 nC		
	0.0087 at V _{GS} = 4.5 V	54			

FEATURES • TrenchFET®

- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested

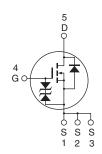
ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting



1, 2, 3 Source 4 Gate 5 Drain



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	80	V		
Gate-Source Voltage	V _{GS}	± 20	v		
	T _C = 25 °C		75 ^a		
Continuous Dunis Comment /T 150 °C)	T _C = 70 °C		62.7	7	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	28.6 ^{b, c}		
	T _A = 70 °C		24.9 ^{b, c}		
Pulsed Drain Current (t = 100 μs)		I _{DM}	250	Α	
Continuous Courses Ducin Die de Coursest	T _C = 25 °C		75a		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	4.5 ^{b, c}		
Single Pulse Avalanche Current	. 0.1!!	I _{AS}	30		
Single Pulse Avalanche Energy L = 0.1 mH		E _{AS}	45	mJ	
	T _C = 25 °C		120		
Manianum Danier Dispiration	T _C = 70 °C	D	80	10/	
Maximum Power Dissipation	T _A = 25 °C	P _D	5 ^{b, c}	W	
	T _A = 70 °C		3.2 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 150			
Soldering Recommendations (Peak Temperature		260	- °C		

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.5	2.0	C/VV	

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. The SOT-669 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder finterconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



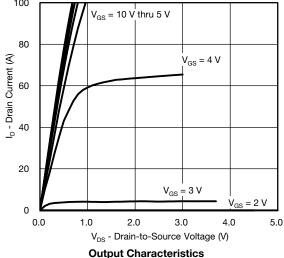
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.1			
Gate-Source Threshold Voltage	V _{GS(th})	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.4		2.6	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0 1 1 1 1 2 1	I _{DSS}	V _{DS} = 80 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		V _{DS} = 80 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Currenta	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0064		1	
		V _{GS} = 6 V, I _D = 15 A		0.0070		Ω	
		$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		0.0087		1	
Forward Transconductancea	9 _{fs}	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S	
Dynamic ^b							
Input Capacitance	C _{iss}	C _{iss}		1855			
Output Capacitance	C _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		950		pF	
Reverse Transfer Capacitance	C _{rss}			76			
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5	54	nC	
Total Gate Charge	Q _g	$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$		22	33		
		$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		17.1	26		
Gate-Source Charge				5.3			
Gate-Drain Charge	Q_{gd}			7.3			
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	R_g	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$ $I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		8	16		
Turn-Off DelayTime	t _{d(off)}			32	64		
Fall Time	t _f			7	14		
Turn-On Delay Time	t _{d(on)}			14	28	ns	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_{L} = 4 \Omega$		11	22	- - -	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			75	^	
Pulse Diode Forward Current (t = 100 μs)	Diode Forward Current (t = 100 μs) I _{SM}				150	A	
Body Diode Voltage	V_{SD}	I _S = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time t _{rr}				38	75	ns	
Body Diode Reverse Recovery Charge		1 10 A 11/14 100 A/ - T 05 20		36	70	nC	
Reverse Recovery Fall Time	ta	IF = 10 A. QI/QT = 100 A/US. 1 1 = 25 °C		19			
Reverse Recovery Rise Time	t _b			19		ns	

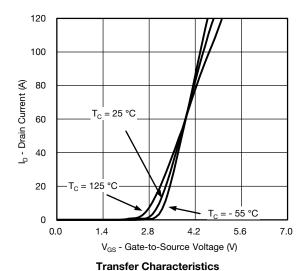
Notes

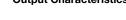
- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

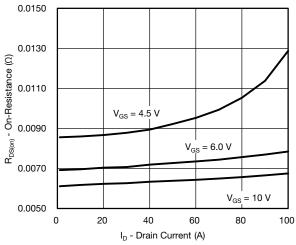
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



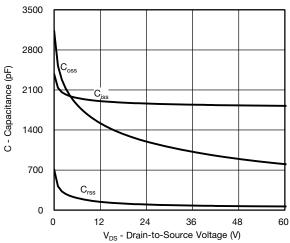




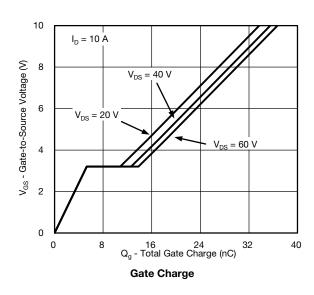




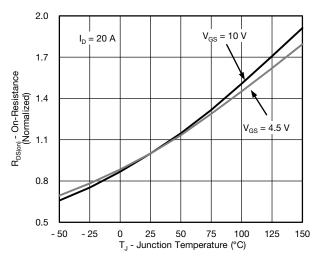




On-Resistance vs. Drain Current



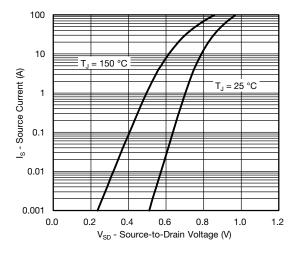




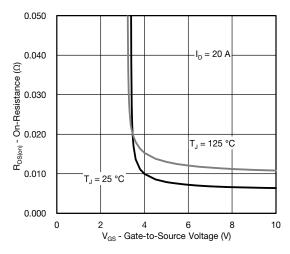
On-Resistance vs. Junction Temperature

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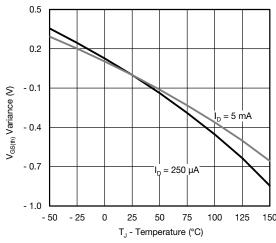




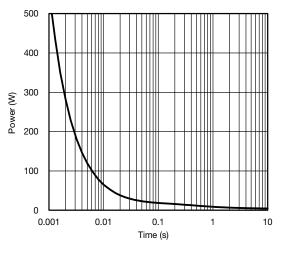
Source-Drain Diode Forward Voltage



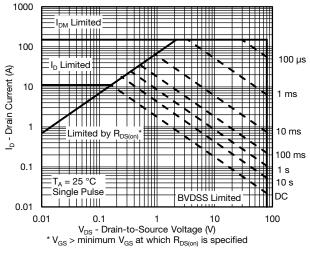
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

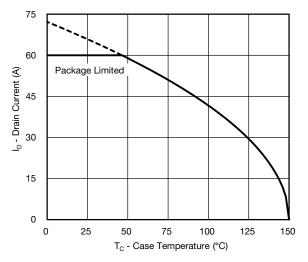


Single Pulse Power, Junction-to-Ambient

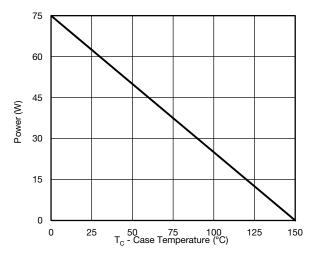


Safe Operating Area, Junction-to-Ambient

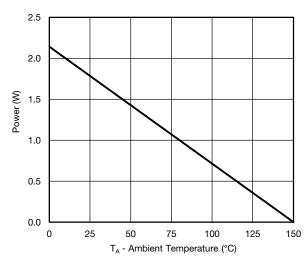




Current Derating*



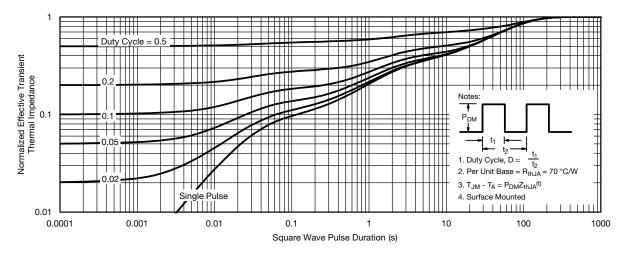




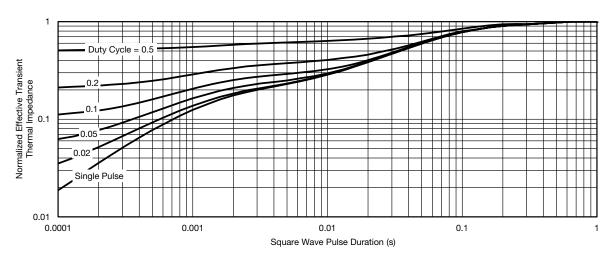
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





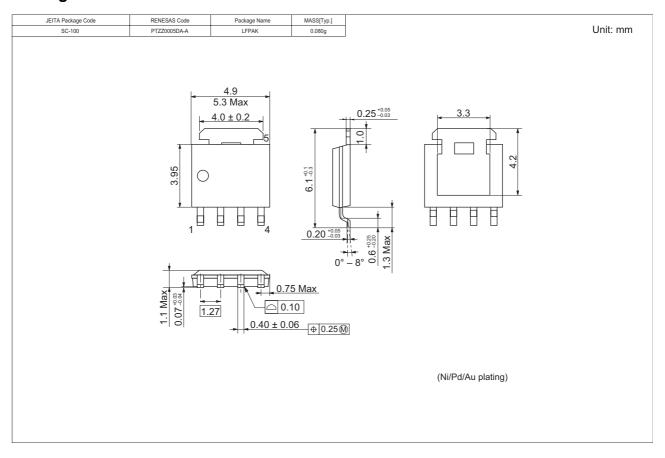
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



Package Dimensions





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